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**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

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Sheet 1 of 1

Complete if Known

Application Number	10/576,342
Filing Date	April 18, 2006
First Named Inventor	DELATTRE, Cyril
Art Unit	1641
Examiner Name	LAM, Ann Y.
Attorney Docket Number	10404.038.00

U.S. PATENT DOCUMENTS

Examiner Initials*	Cite No. ¹	Document Number Number-Kind Code ² (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
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FOREIGN PATENT DOCUMENTS

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NON PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No. ¹	include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
	CA	LEE, Junghoon, et al., Electrowetting And Electrowetting-On-Dielectric For Microscale Liquid Handling, <i>Sensors and Actuators A</i> 95 (2002), pp. 259-268.	
	CB	BRATTEN, Craig D. T., et al., Micromachining Sensors for Electrochemical Measurement in Subnanoliter Volumes, <i>Anal. Chem.</i> 1997, 69, pp. 253-258.	
	CC	YANG, Mengsu, et al. Covalent Immobilization of Oligonucleotides on Modified Glass/Silicon Surfaces for Solid-Phase DNA Hybridization and Amplification, <i>Chemistry Letters</i> 1998, pp. 257-258.	
	CD	BONCHEVA, Mila, et al., Design of Oligonucleotide Arrays at Interfaces, <i>Langmuir</i> 1999, 15, pp. 4317-4320.	
	CE	JANSEN, Henri, et al., The Black Silicon Method: A Universal Method for Determining the Parameter Setting of a Fluorine-Based Reactive Ion Etcher In Deep Silicon Trench Etching With Profile Control, <i>J. Microchem. Microeng.</i> 5 (1995) pp. 115-120.	

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Examiner Signature	/Ann Lam/	Date Considered	10/01/2008
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